

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/663,812 | Applicant(s)/Patent Under Reexamination CHEN ET AL. | |
| | Examiner Brian L. Albertalli | Art Unit 2655 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------------|----------------|
| * | A | US-6,374,210 | 04-2002 | Chu, Ya-Cherng | 704/9 |
| * | B | US-5,953,451 | 09-1999 | Syeda-Mahmood, Tanveer F. | 382/187 |
| * | C | US-6,470,334 | 10-2002 | Umemoto, Hiroshi | 707/3 |
| * | D | US-5,268,840 | 12-1993 | Chang et al. | 704/9 |
| * | E | US-5,319,745 | 06-1994 | Vinsonneau et al. | 715/515 |
| * | F | US-2003/0200211 | 10-2003 | Tada et al. | 707/5 |
| * | G | US-6,879,951 | 04-2005 | Kuo, June-Jei | 704/10 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.